

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.
01FN029US

SERIAL NO.

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use several sheets if necessary)

(37 CFR 1.98(b))

APPLICANT
Hiroaki TANAKA et al.

FILING DATE
May 31, 2001

GROUP

36979 U.S. PTO
09/867423
05/31/01

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
	AJ	4-253028	09-92	Japan			No
	AK						
	AL						
	AM						
	AN						

OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)

	AO	
	AP	
	AQ	

EXAMINER

DATE CONSIDERED

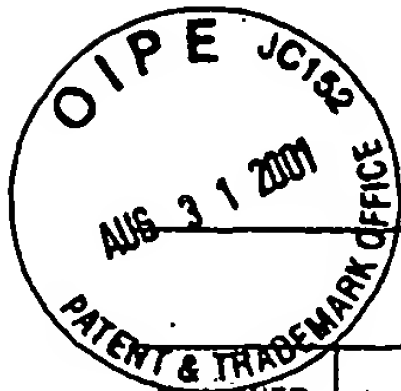
EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered.
Include copy of this form with next communication to applicant.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

(Use several sheets if necessary)

(37 CFR 1.98(b))



ATTY. DOCKET NO.

01FN029US

SERIAL NO.

09/867,423

APPLICANT
Hiroaki TANAKA et al.

FILING DATE
May 31, 2001

GROUP
2971

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA						
AD						

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

	DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
AL	2000-164886	6/00	Japan			Abst.
AM	2001-005038	1/01	Japan			Abst.
AN						
AO						
AP						
AR						
AS						

OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)

AT	Kim, C.W. et al., "A Novel Four-Mask-Count Process architecture for TFT-LCDs", SID 00 Digest, pp. 1006-1009.
AU	
AV	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

(Use several sheets if necessary)

(37 CFR 1.98(b))



ATTY. DOCKET NO.

01FN029US

SERIAL NO.

09/867,423

APPLICANT
Hiroaki TANAKA et al.

FILING DATE
May 31, 2001

GROUP
2971

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA							
AD							

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
	AL	2000-164886	6/00	Japan			Abst.
	AM	2001-005038	1/01	Japan			Abst.
	AN						
	AO						
	AP						
	AR						
	AS						

OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)

	AT	Kim, C.W. et al., "A Novel Four-Mask-Count Process architecture for TFT-LCDs", <u>SID 00 Digest</u> , pp. 1006-1009.
	AU	
	AV	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use several sheets if necessary)

(37 C.F.R. 1.98(b))

ATTY. DOCKET NO.
01FN029US

SERIAL NO.

APPLICANT
Hiroaki TANAKA et al.

FILING DATE
May 31, 2001

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES NO
<i>AKS</i>	AJ	4-253028	09-92	Japan			No
	AK						
	AL						
	AM						
	AN						

OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)

	AO	
	AP	
	AQ	

EXAMINER

[Signature]

DATE CONSIDERED

02-25-05

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.